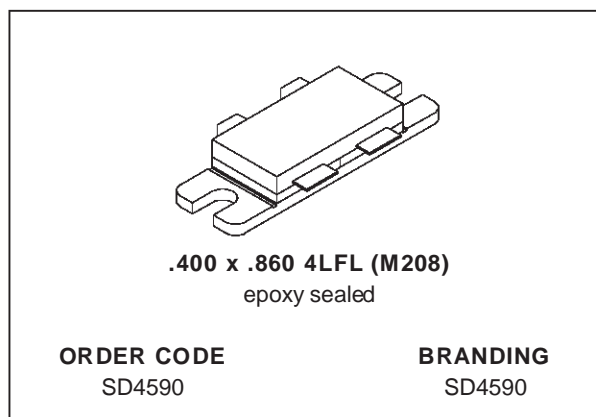


RF & MICROWAVE TRANSISTORS

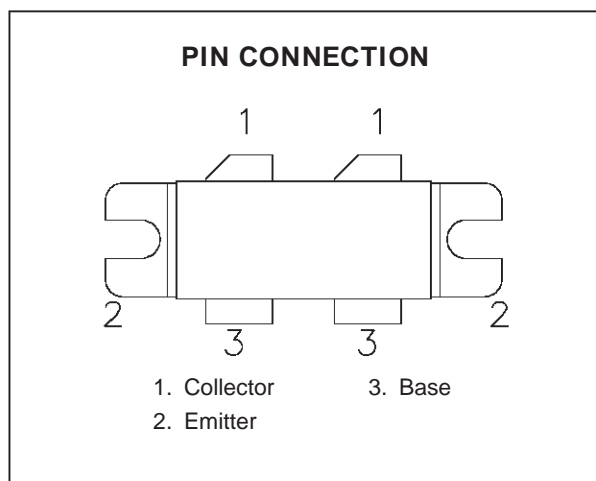
800-960 MHz CELLULAR BASE STATION

- GOLD METALLIZATION
- DIFFUSED EMITTER BALLASTING
- INTERNAL INPUT/OUTPUT MATCHING
- COMMON EMITTER CONFIGURATION
- DESIGNED FOR LINEAR OPERATION
- HIGH SATURATED POWER CAPABILITY
- 26 VOLT, 900 MHz PERFORMANCE
 - $P_{OUT} = 150 \text{ W MIN.}$
 - $GAIN = 8.5 \text{ dB MIN.}$
 - $IMD_3 = -28\text{dB MAX. @ } P_{OUT} = 150\text{W PEP}$
- INHERENT RUGGEDNESS:
 - LOAD MISMATCH TOLERANCE OF 5:1 MIN. VSWR
 - 3 dB OVERDRIVE CAPABILITY



DESCRIPTION

The SD4590 is designed for both analog and digital cellular base stations over the 800 to 960 MHz frequency range, specifically those systems requiring the high linearity and efficiency afforded by class AB operation. Integrated input/output pre-matching simplifies amplifier design. Ruggedness, MTTF, and linearity are enhanced using diffused emitter resistors and refractory/gold metallization.



ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^{\circ}\text{C}$)

Symbol	Parameter	Value	Unit
V_{CBO}	Collector-Emitter Voltage	65	V
V_{CEO}	Collector-Emitter Voltage	28	V
V_{EBO}	Emitter-Base Voltage	3.5	V
I_C	Device Current	25	A
P_{DISS}	Power Dissipation	300	W
T_J	Junction Temperature	+200	$^{\circ}\text{C}$
T_{STG}	Storage Temperature	- 65 to +150	$^{\circ}\text{C}$

THERMAL DATA

$R_{TH(j-c)}$	Junction-Case Thermal Resistance	0.60	$^{\circ}\text{C/W}$
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SD4590

ELECTRICAL SPECIFICATIONS (T_{case} = 25°C)

STATIC

Symbol	Test Conditions	Value			Unit
		Min.	Typ.	Max.	
BV _{CBO}	I _C = 50mA V _{BE} = 0V	65	80	—	V
BV _{CEO}	I _C = 100mA I _B = 0mA	28	30	—	V
BV _{CER}	I _C = 100mA R _{BE} = 75Ω	33	40	—	V
BV _{EBO}	I _E = 10mA I _C = 0mA	3.5	4.0	—	V
I _{CEO}	V _{CE} = 30V V _{BE} = 0V	—	—	10	mA
h _{FE}	V _{CE} = 5V I _C = 6A	25	45	120	—

Tested per side

DYNAMIC

Symbol	Test Conditions	Value			Unit
		Min.	Typ.	Max.	
C _{OB}	f = 1.0 MHz V _{CB} = 26V for information only - this part is collector matched	—	75	—	pF

Tested per side

DYNAMIC (CW)

Symbol	Test Conditions	Value			Unit
		Min.	Typ.	Max.	
P _{IN}	f = 900MHz V _{CE} = 26V I _{CQ} = 2 x 200mA P _{OUT} = 150W	—		21	W
P _{OUT}	f = 900MHz V _{CE} = 26V I _{CQ} = 2 x 200mA P _{IN} = 21W	150	175		W
G _P	f = 900MHz V _{CE} = 26V I _{CQ} = 2 x 200mA P _{OUT} = 150W	8.5	9.5	—	dB
η _C	f = 900MHz V _{CE} = 26V I _{CQ} = 2 x 200mA P _{OUT} = 150W	50	55	—	%
P _{1dB}	f = 900MHz V _{CE} = 26V I _{CQ} = 2 x 200mA	150	160		W
OVD	f = 900MHz V _{CC} = 26V I _{CQ} = 2 x 200mA Set P _{OUT} = 150W; Increase P _{IN} 3dB	No Degradation in Device Performance			

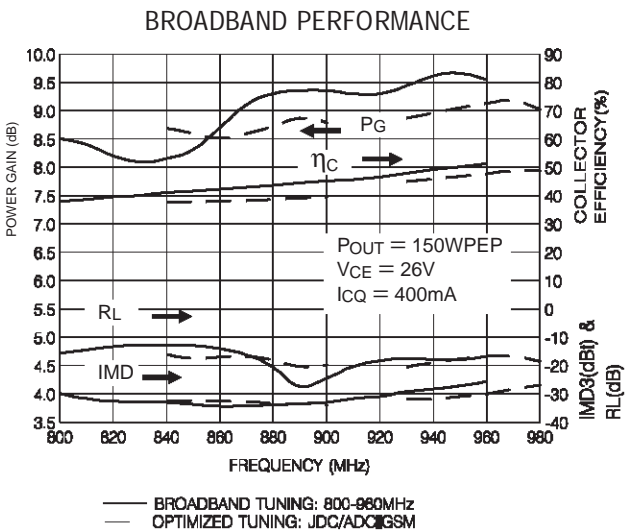
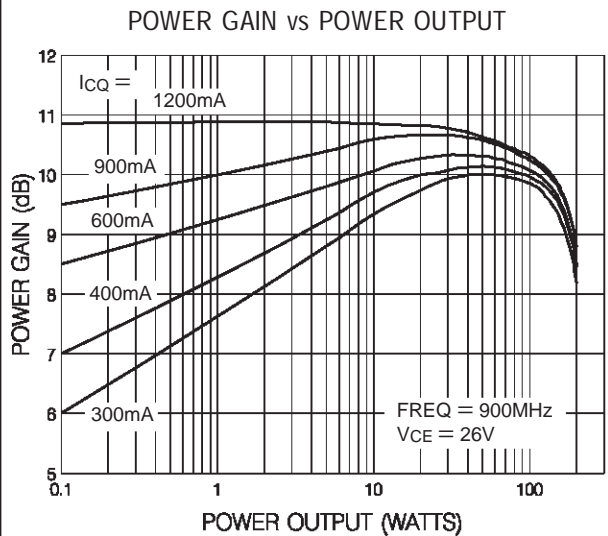
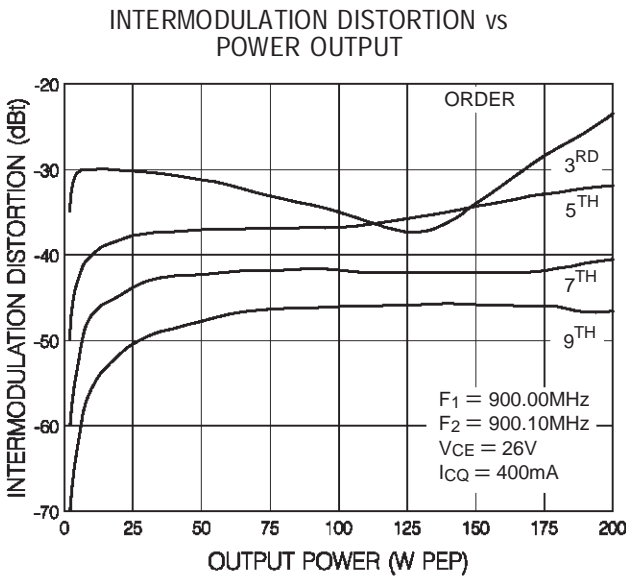
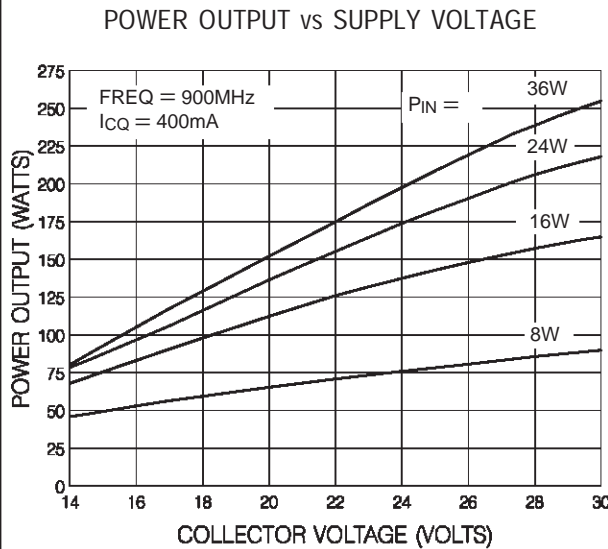
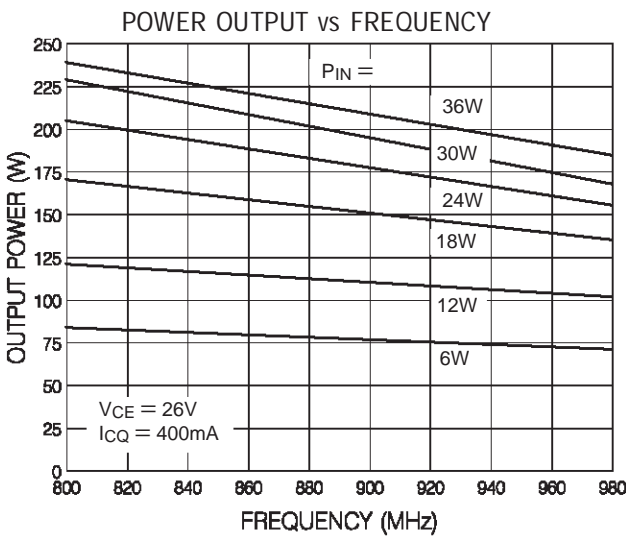
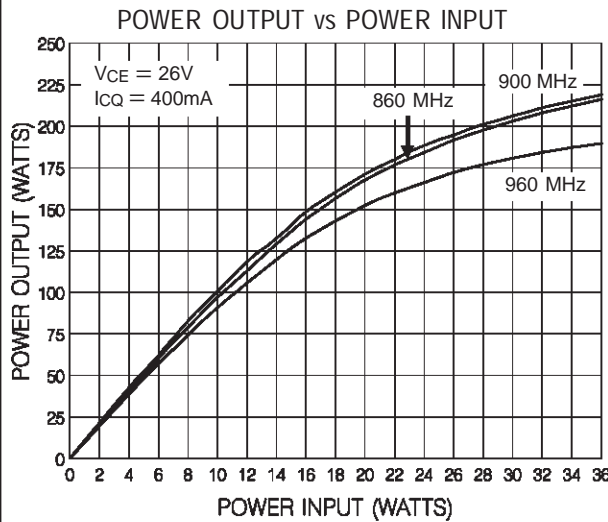
DYNAMIC (Two-Tone)

Symbol	Test Conditions	Value			Unit
		Min.	Typ.	Max.	
*G _P	V _{CE} = 26V I _{CQ} = 2 x 200mA P _{OUT} = 150W PEP	8.5	9.5	—	dB
*η _C	V _{CE} = 26V I _{CQ} = 2 x 200mA P _{OUT} = 150W PEP	30	35	—	%
*IMD ₃	V _{CE} = 26V I _{CQ} = 2 x 200mA P _{OUT} = 150W PEP	—	−32	−28	dB
*Load Mismatch	V _{CE} = 26V I _{CQ} = 2 x 200mA P _{OUT} = 150W PEP VSWR = 5:1 MIN @ All phase angles	No Degradation in Device Performance			
*OVD	V _{CE} = 26V I _{CQ} = 2 x 200mA Set P _{OUT} = 150W PEP; Increase P _{IN} 3dB	No Degradation in Device Performance			

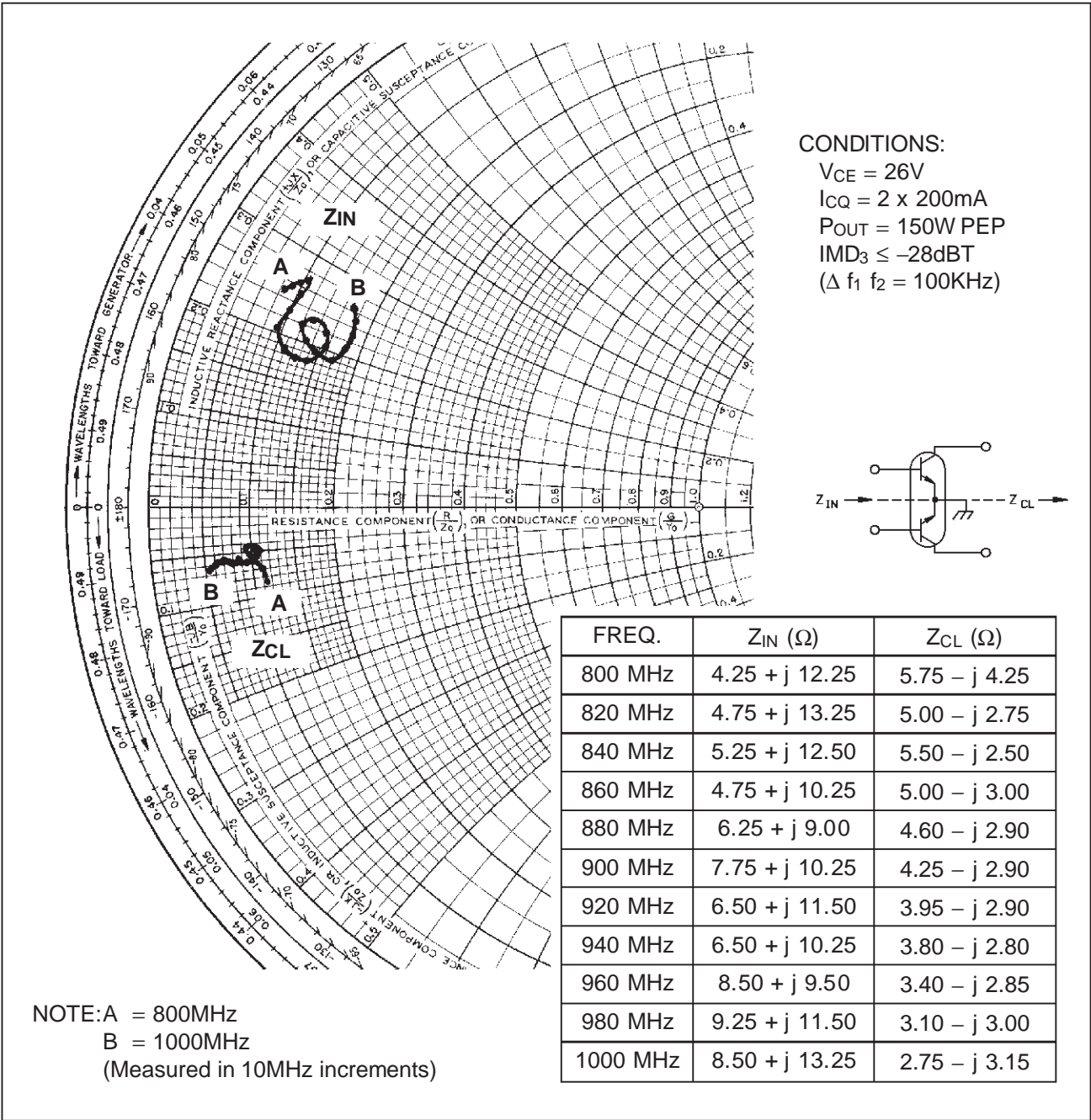
*Note: f₁ = 900.00 MHz

f₂ = 900.10 MHz

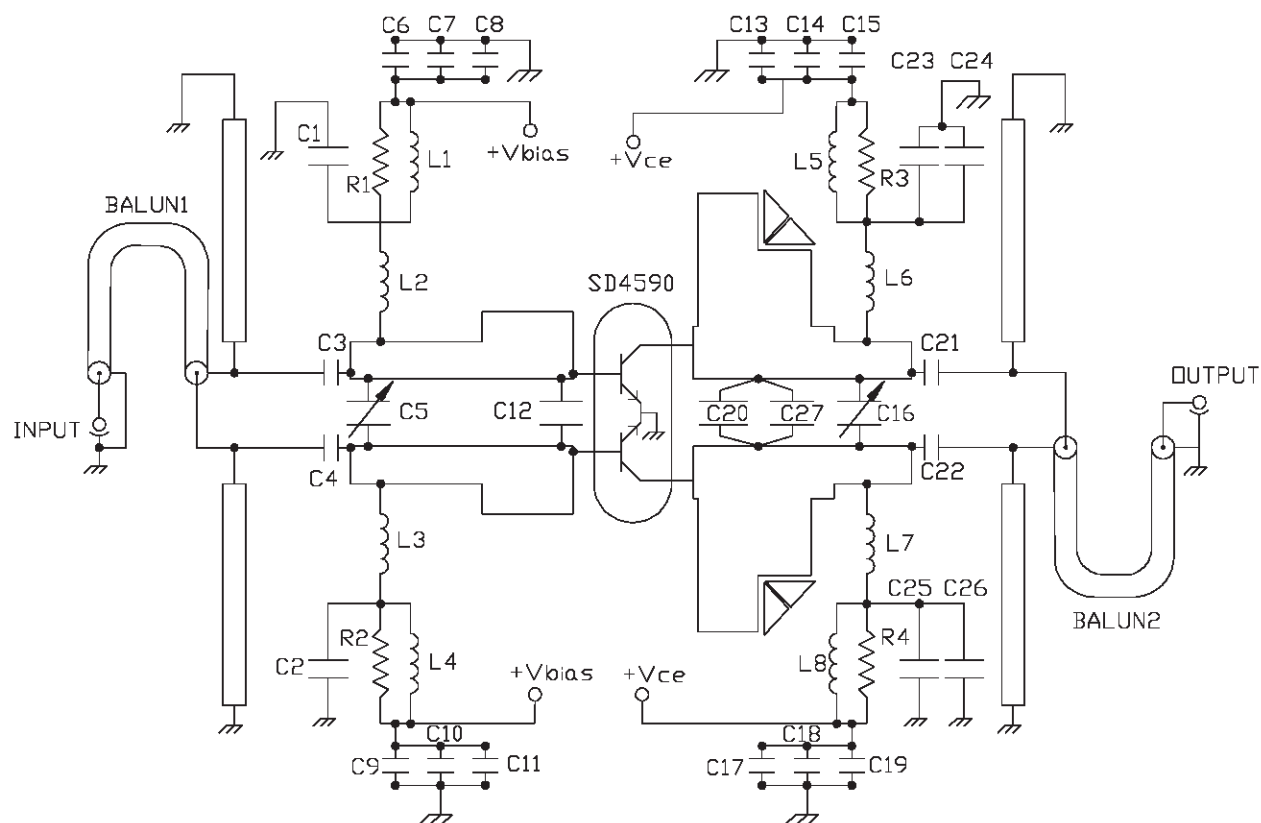
TYPICAL PERFORMANCE



SERIES EQUIVALENT INPUT/OUTPUT IMPEDANCES



TEST CIRCUIT



Balun 1, 2 : 50 Ω Coaxial Cable Length 2.2"

C1, C2, C23, C25 : 75pF Ceramic Chip, ATC B
 C3, C4, C21, C22 : 2 x 47pF Ceramic Chip, ATC B
 C5, C16 : 0.8 - 8pF Variable, JOHANSON Giga-Trim
 C6, C9 : 750pF Ceramic Chip, ATC B
 C7, C10 : 39nF Ceramic Chip, ATC B
 C8, C11, C24, C26 : 47 μ F, 50V Electrolytic
 C13, C17 : 100 μ F, 50V Electrolytic
 C12 : 9.1pF, Ceramic Chip, ATC A
 C14, C18 : 39nF Ceramic Chip (OPTIONAL)
 C15, C19 : 750pF Ceramic Chip (OPTIONAL)

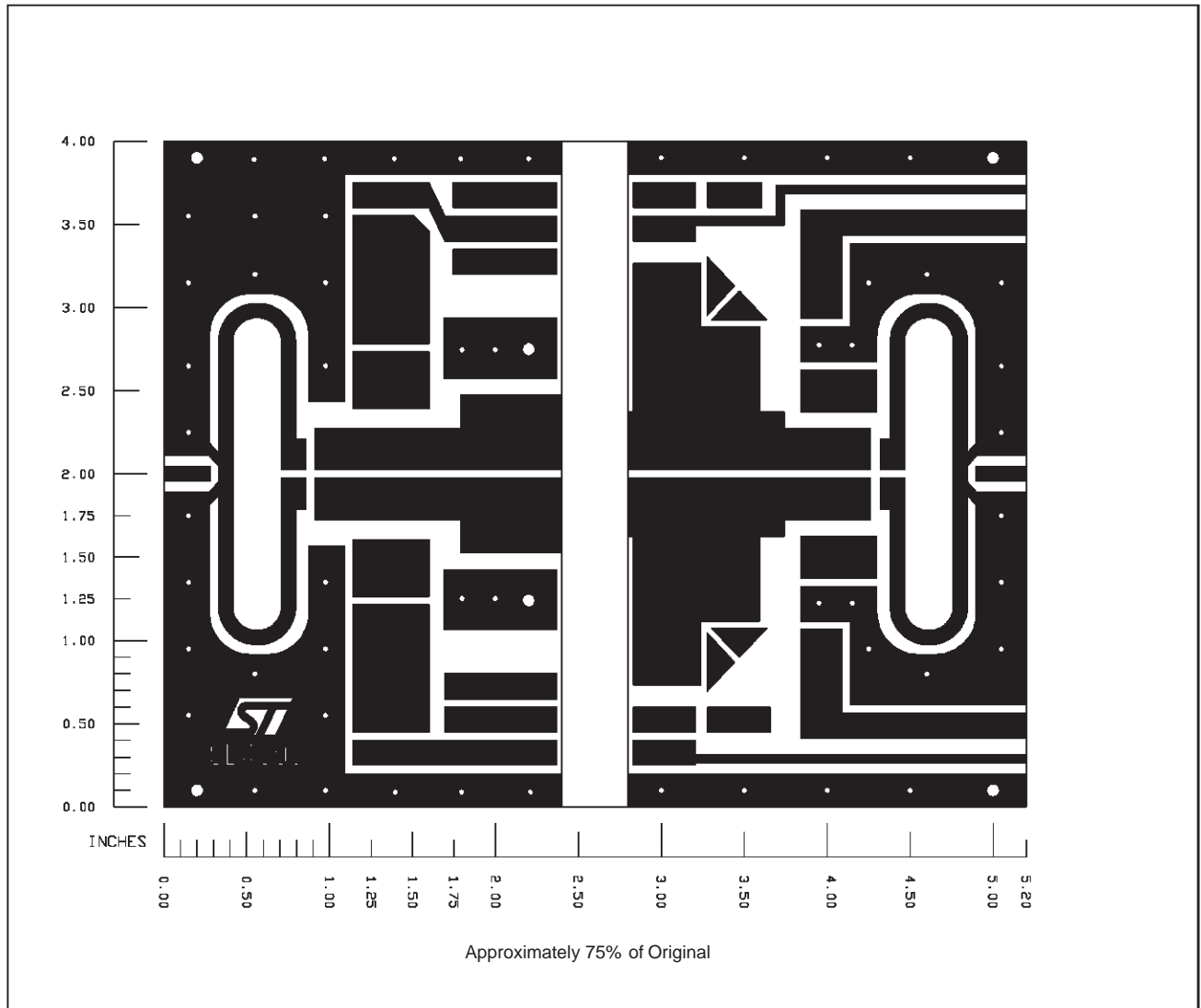
C20 : 1.3pF Ceramic Chip, ATC B
 C27 : 0.7pF Ceramic Chip, ATC B

L1, L4, L5, L8 : 12 Turns, #20 AWG, 0.15" I.D. (Tight)
 L2, L3, L6, L7 : 4 Turns, #20 AWG, 0.13" I.D. (1:1)

R1, R2, R3, R4 : 5 x 50 Ω Chip Resistor

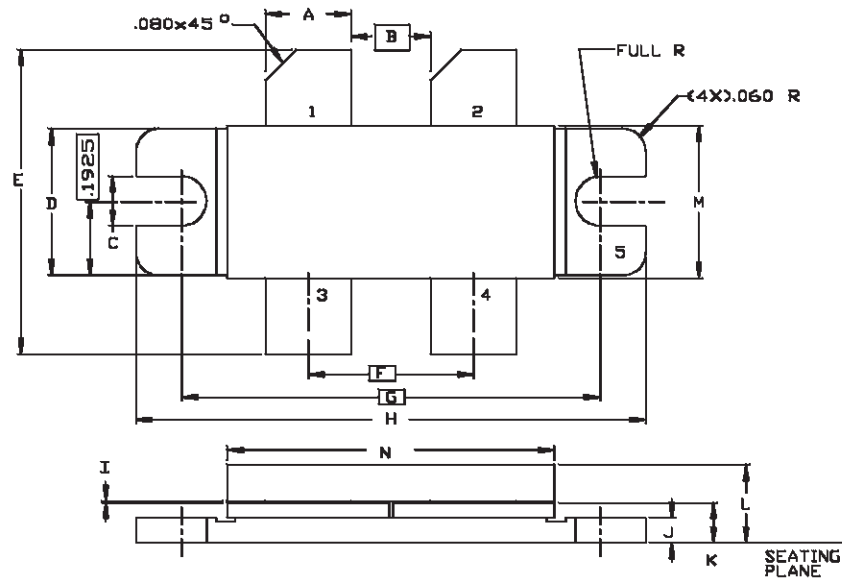
Board Material : ROGERS, Er = 2.55, Height = 31.25 mil
 1 oz. Cu.
 See Photomaster for Microstrip Lines.

PHOTOMASTER OF TEST CIRCUIT



PACKAGE MECHANICAL DATA

Ref.: Dwg. No.12-0208
UDCS No. 1011409 rev C



SGS-THOMSON MICROELECTRONICS			CONT'D		
	MINIMUM Inches/mm	MAXIMUM Inches/mm		MINIMUM Inches/mm	MAXIMUM Inches/mm
A	.220/5,59	.230/5,84	K	.082/2,08	.100/2,54
B	.210/5,33		L		.205/5,21
C	.120/3,05	.130/3,30	M	.395/10,03	.407/10,34
D	.380/9,65	.390/9,91	N	.850/21,59	.870/22,10
E	.780/19,81	.820/20,83			
F	.435/11,05				
G	1.100/27,94				
H	1.335/33,91	1.345/34,16			
I	.003/0,08	.007/0,18			
J	.060/1,52	.070/1,78			

PIN: 1. COLLECTOR
2. COLLECTOR
3. BASE
4. BASE
5. EMITTER

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